

PATDPA

Subject Coverage	<ul style="list-style-type: none"> All areas of science and technology, i.e., all classes of the International Patent Classification 																												
File Type	Bibliographic																												
Features	<table border="0"> <tr> <td>Thesaurus</td> <td colspan="4">International Patent Classification (/IPC)</td> </tr> <tr> <td>Alerts (SDIs)</td> <td colspan="4">Not available</td> </tr> <tr> <td>CAS Registry Number[®] Identifiers</td> <td><input type="checkbox"/></td> <td>Page Images</td> <td><input type="checkbox"/></td> <td>STN[®] AnaVist[™]</td> <td><input type="checkbox"/></td> </tr> <tr> <td>Keep & Share</td> <td><input checked="" type="checkbox"/></td> <td>SLART</td> <td><input checked="" type="checkbox"/></td> <td>STN Easy[®]</td> <td><input checked="" type="checkbox"/></td> </tr> <tr> <td>Learning Database</td> <td><input checked="" type="checkbox"/></td> <td>Structures</td> <td><input type="checkbox"/></td> <td></td> <td></td> </tr> </table>	Thesaurus	International Patent Classification (/IPC)				Alerts (SDIs)	Not available				CAS Registry Number [®] Identifiers	<input type="checkbox"/>	Page Images	<input type="checkbox"/>	STN [®] AnaVist [™]	<input type="checkbox"/>	Keep & Share	<input checked="" type="checkbox"/>	SLART	<input checked="" type="checkbox"/>	STN Easy[®]	<input checked="" type="checkbox"/>	Learning Database	<input checked="" type="checkbox"/>	Structures	<input type="checkbox"/>		
Thesaurus	International Patent Classification (/IPC)																												
Alerts (SDIs)	Not available																												
CAS Registry Number [®] Identifiers	<input type="checkbox"/>	Page Images	<input type="checkbox"/>	STN [®] AnaVist [™]	<input type="checkbox"/>																								
Keep & Share	<input checked="" type="checkbox"/>	SLART	<input checked="" type="checkbox"/>	STN Easy[®]	<input checked="" type="checkbox"/>																								
Learning Database	<input checked="" type="checkbox"/>	Structures	<input type="checkbox"/>																										
Record Content	<ul style="list-style-type: none"> Bibliographic data and legal status of all kinds of patent documents and utility models published by Deutsches Patent- und Markenamt (German Patent- and Trademark-Office) as well as all kinds of patent documents of the European Patent Office and the World Intellectual Property Organization (WIPO) designated for the Federal Republic of Germany. The German patent documents contain abstracts since 1981, main claims of German translations of granted European patents since June 1992 and main claims of all granted German patents since January 1996. European patent documents contain abstracts of applications filed in German language since August 1998 and main claims of all granted European patents since August 1998. WIPO patent documents contain abstracts of applications filed in German language since August 1998. 																												
File Size	<ul style="list-style-type: none"> 7.881.372 records 																												
Coverage	1968-June 2011																												
Updates	Closed file																												
Language	German																												
Database Producer	Deutsches Patent- und Markenamt Zweibrückenstr. 12 80331 München Germany Phone: +49 89/2195-1 Fax: +49 89/2195-2221 Copyright Holder																												

Database Supplier FIZ Karlsruhe
STN Europe
P.O. Box 2465
76012 Karlsruhe
Germany
Phone: +49 7247 808-555
Fax: +49 7247 808-259
Email: helpdesk@fiz-karlsruhe.de

- Sources**
- German patent publications starting with first publication and update by following ones (Offenlegungsschriften, Auslegeschriften, Patentschriften)
 - German utility model publications since 1968
 - Designated EP- and PCT-applications since 1978
-

- User Aids**
- Online Helps (HELP DIRECTORY lists all help messages available)
 - STNGUIDE
-

- Clusters**
- ALLBIB
 - CORPSOURCE
 - HPATENTS
 - PATENTS
- [STN Database Clusters](#) information (PDF)
-

- Related Databases**
- PATDPASPC
-

Pricing Enter HELP COST at an arrow prompt.

Search and Display Field Codes

Fields that allow left truncation are indicated by an asterisk (*).

General Search Fields

Search Field Name	Search Code	Search Examples	Display Codes
Basic Index *(contains single words from Title (TI), Abstract (AB), and Main Claim (MCLM) fields)	None or /BI	S KUEHLUNG(S)ACHSE?	TI, AB, MCLM
Accession Number	/AN	S DE69700021/AN	AN
Agent	/AG	S ZAHN ROLAND/AG	AG
Agent Number	/AGN	S 120626/AGN	AGN
Application Country	/AC	S EP/AC	AI
Application Date (1)	/AD	S 19820107/AD	AI
Application Kind Code	/AK	S DEA/AK	AI
Application Number (2)	/AP	S DE1981-3152498/AP	AI
	(or /AI)	S 1981DE-3152498/AP	
Application Type	/AT	S ADP/AT	AI
Application Year (1)	/AY	S 1983/AY	AI
Classification Code (code and text) (3)	/CC	S UMWELTSCHUTZ/CC	CC
Data Entry Date (1)	/DED	S DED>DEC 2008	DED
Data Entry Week (1)	/DEW	S 199829/DEW	DEW
Designated State	/DS	S W DE/DS	PI, DS
Document Type	/DT	S U/DT	DT
Entry Date (1)	/ED	S 19981015/ED	ED
Entry Date Abstract or Main Claim (1)	/EDAB	S EDAB>=FEB 2009	EDAB
Entry Week	/EW	S EW=200901	EW
Family Member Application Country	/FAC	S WO/FAC	FIA
Family Member Application Date (1)	/FAD	S 18 Nov 1998/FAD	FIA
Family Member Application Kind Code	/FAK	S EPAW/FAK	FIA
Family Member Application Number (2)	/FAP	S DE1998-19800050/FAP	FIA
		S 1998DE-19800050/FAP	
Family Member Application Type	/FAT	S ADU/FAT	FIA
Family Member Application Year (1)	/FAY	S 1998/FAY	FIA
Family Member Country	/FC	S DE/FC	FIP
Family Member Kind Code	/FK	S DEA1/FK	FIP
Family Member Number (2)	/FN	S DE3152498/FN	FIP
Family Member Publication Date (1)	/FD	S 820101-820331/FD	FIP
Family Member Publication Type	/FPT	S UGO/FPT	FIP
Family Member Year (1)	/FY	S 1983/FY	not displayed
Field Availability	/FA	S KUEHLUNG AND AB/FA	FA
International Patent Classification (ICM, ICS)	/IC	S B60B007-02/IC	IC
		S B60B007/IC	
Inventor (current and old)	/IN	S SCHULTE/IN	IN
Inventor Address (current)	/INA	S BERLIN/INA	IN
Inventor Current	/INC	S AHL, T?/INC	IN
Inventor Old	/INO	S HAAG, F?/INO	IN
IPC (contains ICA, ICI, ICM, ICMO, ICS, ICSO, IPCI) (4,5)	/IPC	S H05B006-36/IPC	IC, IPC
IPC, Action Date	/IPC.ACD	S 20060101/IPC.ACD	IPC.TAB
IPC, Additional (supplementary)	/ICA	S F01L001-04/ICA	ICA
IPC, Index (complementary)	/ICI	S C07D205:08/ICI	ICI
IPC, Initial	/IPCI	S B60K/IPCI	IPC.TAB
IPC, Keyword Terms	/IPC.KW	S L1 AND INITIAL/IPC.KW	IPC.TAB

PATDPA

General Search Fields (continued)

Search Field Name	Search Code	Search Examples	Display Codes
IPC, Main (current)	/ICM	S B21B001-00/ICM	ICM, IC
IPC, Main Old	/ICMO	S B60B011-02/ICMO	ICMO
IPC, Secondary (current)	/ICS	S C01B003-12/ICS	ICS, IC
IPC, Secondary Old (with concordance)	/ICSO	S H01J023-36/ICSO	ICSO
IPC, Version (1)	/IPC.VER	S 200601/IPC.VER	IPC.TAB
Language (code and text)	/LA	S EN/LA	LA
Last Note (last legal status code)	/NTL	S AOR/NTL	NTL
Last Note Date (last legal status date) (1)	/NTDL	S L1 AND NTLD>JUL 2008	NTL
Main Group of IPC (range searchable) (1,6)	/MGR	S H01R/ICM(L)15-23/MGR	ICM
National Patent Classification	/NCL	S 12D 1-03/NCL	NCL
Note (legal status code)	/NTE	S ADR/NTE	NTE
Note Date (legal status date) (1)	/NTD	S 831 120/NTD	NTE
Opposition (3)	/OP	S DAIMLER BENZ/OP	OP
Other Source	/OS	S CA/OS	OS
Passat Terms	/PST	S TRANSISTOR/PST	PST
Patent Assignee (current and old) (4)	/PA (or /CS)	S FAMAG/PA S FAMATEX?/PA	PA, PAO
Patent Assignee Address (current) (3)	/PAA	S KARLSRUHE/PAA	PA, PAA, PAO
Patent Assignee Current (3)	/PAC	S GIAMPAOLO/PAC	PA
Patent Assignee Number	/PAN	S 0100020/PAN	PAN
Patent Assignee Old (3)	/PAO	S PODBELCEV?/PAO	PA, PAO
Patent Assignee Type (current)	/PAT	S CORP/PAT	PAT
Patent Country	/PC	S EP/PC	PI
Patent Information Publication Type	/PIT	S OSDE/PIT	PIT
Patent Kind Code	/PK	S DEA1/PK	PI
Patent Kind Code (Max)	/PK.M	S EPA1/PK.M	PI, PI.M
Patent Number (2)	/PN (or /PI)	S DE1302622/PN	PI
Patent Sequence Reference	/PSR	S WO8001016/PSR	PSR
Patent Type	/PT	S OP3/PT	PI
Patent Type (Max)	/PT.M	S AOTW/PT.M	PI
Patent Week (1)	/PW	S 1988440/PW	not displayed
Priority Country	/PRC	S AU/PRC	PRAI
Priority Date (1)	/PRD	S PRD=JAN 2009	PRAI
Priority Kind Code	/PRK	S DEA/PRK	PRAI
Priority Number (2)	/PRN (or /PRAI)	S FR1992-15537/PRN S 1992FR-0015537/PRN	PRAI
Priority Type	/PRT	S WP/PRT	PRAI
Priority Year (1)	/PRY	S 1980/PRY	not displayed
Publication Date (1)	/PD	S 19820100-19820630	PI
Publication Date (Max) (1)	/PD.M	S 19990128/PD.M	PI, PI.M
Publication Year (1)	/PY	S 1985/PY	not displayed
Publication Year (Max) (1)	/PY.M	S 1999/PY.M	PI
Referenced Non-Patent Literature	/REN	S KRAFTWERKSTECHNIK/REN	RE,REN
Referenced Patent Country	/RPC	S DE/RPC	REP
Referenced Patent Kind Code	/RPK	S DEA/RPK	REP
Referenced Patent Number (2)	/RPN	S DE2750426/RPN	REP
Referenced Patent Type	/RPT	S SRN/RPT	REP
Related Application Country	/RLC	S DE/RLC	RLI
Related Application Date (1)	/RLD	S 20090102/RLD	RLI
Related Application Kind Code	/RLK	S DEA3/RLK	RLI
Related Application Number (2)	/RLN	S DE1981-3120021/RLN	RLI

General Search Fields (continued)

Search Field Name	Search Code	Search Examples	Display Codes
Related Application Type	/RLT	S DIV/RLT	RLI
Related Application Year (1)	/RLY	S RLY>1997	RLI
Subgroup of IPC (range searchable) (6)	/SGR	S B60B007/ICS(L)2100>SGR	ICS
System Number (AKZ or Serial No.)	/SN	S DE3152498.2/SN	SN
Title	/TI	S ACHSENSTEUERUNG/TI	TI
Update Date (1)	/UP	S 19810312/UP	UP
Update Date Abstract (1)	/UPAB	S DEC 1998/UPAB	UPAB
Update Date Family Information (1)	/UPFI	S 10 DEC 1998/UPFI	UPFI
Update Date Note Information (1)	/UPNT	S 19981203/UPNT	UPNT
Update Date Patent Assignee (1)	/UPPA	S UPPA=29 Jul 1999	UPPA
Update Date Patent Information (1)	/UPPI	S 19981203/UPPI	UPPI
Update Date Patent Kind Code (1)	/UPPK	S UPPK>JAN 2009	DED, UPPK
Update Date SDI (last update) (1)	/UPS	S UPS=19981210	UPS

(1) Numeric search field that may be searched using numeric operators or ranges.

(2) Either STN or Derwent format may be used.

(3) Search with implied (S) proximity is available in this field.

(4) An online thesaurus is available in this field.

(5) PATDPA does currently not cover IPC reclassification data.

(6) Only valid for version 1-7.

Super Search Fields

Enter a super search code to execute a search in one or more fields that may contain the desired information. Super search fields facilitate crossfile and multifile searching. EXPAND may not be used with super search fields. Use EXPAND with the individual field codes instead.

Search Field Name	Search Code	Fields Searched	Search Examples	Display Codes
Application Number Group (1)	/APPS	/AP, /PRN, /RLN, /FAP	S DE1996-19601116/APPS	AI, PRAI
Patent Countries	/PCS	/PC, /DS	S DE/PCS	PI, DS
Patent Number Group (1)	/PATS	/PN, /FAP, /RPN	S EP100323/PATS	PI, REP

(1) Either STN or Derwent format may be used.

IPC THESAURUS

The classifications, validity and catchwords for the main headings and subheadings from the current (8th) edition of the WIPO International Patent Classification (IPC) manual are available. The classifications from the previous editions (1-7) are also available as separate thesauri. To EXPAND and SEARCH in the thesauri for editions 1-8, use the field code followed by the edition number, e.g., /IPC2 for the 2nd edition. Catchwords are included only in the thesauri for the 8th, 7th, 6th, and 5th editions. The IPC thesauri are available for records from 1967 to the present.

Code	Content	Examples
ADVANCED (ADV)	Advanced Level Codes for the Core Level IPC Code	E A61K0066-02+ADVANCED/IPC
ALL	All Associated Terms (BT, SELF, NT, RT)	E C01C003-00+ALL/IPC
BRO (MAN)	Complete Class	E C01C+BRO/IPC
BT	Broader Term (SELF, BT)	E C01F001-00+BT/IPC
CORE (COR)	Core Codes for the Advanced Level IPC Code	E G08C0019-22+CORE/IPC
ED	Complete title of the SELF term and IPC manual	E C01F001-00+ED/IPC
HIE	Hierarchy Term (Broader and Narrower Term) (BT, SELF, NT)	E C011003-00+HIE/IPC

IPC THESAURUS (cont'd)

Code	Content	Examples
INDEX	Complete title of the SELF term	E C01F001-00+INDEX/IPC
KT	Keyword Term (catchwords) (SELF, KT)	E CYANOGEN+KT/IPC
NEXT	Next Classification	E C01C001-00+NEXT5/IPC
NT	Narrower Terms (SELF, NT)	E C01C+NT/IPC
PREV	Previous Classification	E C01C001-12+PREV10/IPC
RT (SIB)	Related Terms (SELF, RT)	E C01C003-20+RT/IPC
TI	Complete Title of the SELF Term and Broader Terms (BT, SELF)	E C01F001-00+TI/IPC

DISPLAY and PRINT Formats

Any combination of formats may be used to display or print answers. Multiple codes must be separated by spaces or commas, e.g., D L1 1-5 TI AU. The fields are displayed or printed in the order requested.

Hit-term highlighting is available for most searchable fields. Highlighting must be ON during SEARCH to use the HIT, KWIC, and OCC formats.

Format	Content	Examples
AB	Abstract	D TI AB 1-5
AG	Agent	D AG
AGN	Agent Number	D AGN
AI (1)	Application Information	D AI
AN	Accession Number	D L3 AN
CC	Classification Code	D CC
DED	Data Entry Date	D DED
DEW	Data Entry Week	D DEW
DS	Designated State (includes PI)	D DS
DT	Document Type	D DT LA
ED	Entry Date	D ED
EDAB (2)	Entry Date Abstract or Main Claim	D EDAB
EW	Entry Week	D EW
EXF	Examiner Field	D EXF
FA	Field Availability	D FA
FI (1)	Family Information	D FI
FIA (1)	Family Application Information	D FIA
FIP (1)	Family Publication Information	D FIP
IC	International Patent Classification (ICM, ICS)	D IC
ICA	IPC, Additional (Supplementary)	D ICA
ICI	IPC, Index (Complementary)	D ICI
ICM	IPC, Main (current)	D ICM
ICMO	IPC, Main Old	D ICMO
ICS	IPC, Secondary (current)	D ICS
ICSO	IPC, Secondary Old (with concordance)	D ICSO
IN	Inventor (INC, INO)	D IN
INC (2)	Inventor Current	D INC
INO (2)	Inventor Old	D INO
IPCI	IPC, Initial	D IPCI
LA	Language	D LA
MCLM	Main Claim	D MCLM
NCL	National Patent Classification	D NCL
NTE (NTL)	Note (legal status date, code and text)	D NTE
OP	Opposition	D OP
OS	Other Source	D OS

DISPLAY and PRINT Formats (cont'd)

Format	Content	Examples
PA PAA (2) PAC (2) PAN PAO (2) PAT PI (1) PI.M (1) PIT PRAI (1) PSR PST RE REN REP (1) RLI (1) SN SO SPC TI TI.M TIEN UP UPAB (2) UPFI (2) UPNT (2) UPPA (2) UPPI (2) UPPK UPS	Patent Assignee (PAC, PAO) Patent Assignee Address Patent Assignee Current Patent Assignee Number Patent Assignee Old Patent Assignee Type Patent Information Patent Information (Max) Patent Information Publication Type Priority Information Patent Sequence Reference Passat Term Reference Patent and Non-Patent Literature (includes REP, REN) Referenced Non-Patent Literature Referenced Patent Literature Related Application Information System Number (AKZ or Serial No.) Source Supplementary Protection Certificate Title Titles Title in English Update Date Update Date Abstract Update Date Family Information Update Date Note Information Update Date Patent Assignee Update Date Patent Information Update Date Patent Kind Code Update Date (SDI)	D PA D PAA D PAC D PAN D PAO D PAT D PI D PI.M D PIT D PRAI D PSR D PST D RE D REN D REP D RLI D SN D SO D SPC D TI D TI.M D TIEN D UP D UPAB D UPFI D UPNT D UPPA D UPPI D UPPK D UPS
ABS ALL IALL (ALLU) BIB IBIB (BIBU) BRIEF IND IPC IPC.TAB MAX STD ISTD (STDU) SCAN (3) TRIAL (TRI, SAM)	AN, ED, EW, SN, DED, DEW, UPS, AB, MCLM AN, ED, EW, SN, DED, DEW, UPS, TI, TIEN, IN, PA, AN, PAT, AG, AGN, EXF, SO, DT, LA, NTE, PIT, PI, DS, AI, RLI, PRAI, FI, RE, OS, IPC, NCL, CC, AB, MCLM, FA, OP ALL, indented with headlines AN, ED, EW, SN, DED, DEW, UPS, TI, TIEN, IN, PA, PAN, PAT, AG, AGN, EXF, SO, DT, LA, PIT, PI, DS, AI, RLI, PRAI, FI, RE, OS BIB, indented with headlines AN, ED, EW, SN, DED, DEW, UPS, TI, TIEN, IN, PA, PAN, PAT, AG, AGN, EXF, SO, DT, LA, PIT, PI, DS, AI, RLI, PRAI, FI, RE, OS, IPC, NCL, CC, AB, MCLM, FA IPC, CC International Patent Classification (ICM, ICMO, ICS, ICSO, ICA, ICI, IPCI) IPC, IPC.KW, IPC.ACD, IPC.VER, Tabular Display AN, ED, EW, SN, DED, DEW, UPS, TI.M, TIEN, IN, PA, PAN, PAT, AG, AGN, EXF, SO, DT, LA, NTE, PIT, PI.M, DS, AI, RLI, PRAI, FI, SPC, RE, OS, IPC, NCL, CC, AB, MCLM, PST, FA, OP, ED, UP AN, ED, EW, SN, DED, DEW, UPS, TIEN, IN, PA, PAN, PAT, AG, AGN, EXF, SO, DT, LA, PIT, PI, DS, AI, RLI, PRAI, FI, RE, OS, IPC, NCL, CC STD, indented with headlines TI (random display without answer numbers) TI, IPC, NCL, CC	D ABS D ALL D IBIB D BRIEF D MAX
HIT KWIC OCC	Hit term(s) and field(s) Up to 50 words before and after hit term(s) (KeyWord-In-Context) Number of occurrences of hit term(s) and field(s) in which they occur	D HIT D KWIC D OCC

PATDPA

- (1) By default, patent numbers, application and priority numbers are displayed in STN format. To display them in Derwent format, enter SET PATENT DERWENT at an arrow prompt. To reset display to STN format, enter SET PATENT STN.
- (2) Custom display only.
- (3) SCAN must be specified on the command line, i.e., D SCAN or DISPLAY SCAN.

SELECT, ANALYZE, and SORT Fields

The SELECT command is used to create E-numbers containing terms taken from the specified field in an answer set.

The ANALYZE command is used to create an L-number containing terms taken from the specified field in an answer set.

The SORT command is used to rearrange the search results in either alphabetic or numeric order of the specified field(s).

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Abstract	AB	Y (2)	N
Accession Number	AN	Y	N
Agent	AG	Y	Y
Agent Number	AGN	Y	Y
Application Country	AC	Y	Y
Application Date	AD	Y	Y
Application Kind Code	AK	Y	Y
Application Number	AP (AI)	Y (3)	Y
Application Number Group	APPS	Y (4)	N
Application Type	AT	Y	Y
Application Year	AY	Y	Y
Classification Code	CC	Y	Y
Data Entry Date	DED	Y	Y
Data Entry Week	DEW	Y	Y
Data Update Date	DUP	Y	N
Designated States	DS	Y	Y
Document Type	DT (TC)	Y	Y
Entry Date	ED	Y	Y
Entry Date Abstract or Main Claim	EDAB	Y	N
Entry Week	EW	Y	Y
Examiner's Field	EXF	Y	Y
Family Application Information	FIA	Y	N
Family Information	FI	Y (3,5)	N
Family Member Application and Patent Numbers	FN	Y (3)	N
Family Member Application Country	FAC	Y	N
Family Member Application Date	FAD	Y	N
Family Member Application Kind Code	FAK	Y	N
Family Member Application Number	FAP	Y	N
Family Member Application Type	FAT	Y	N
Family Member Application Year	FAY	Y	N
Family Member Country	FC	Y	N
Family Member Date	FD	Y	N
Family Member Kind Code	FK	Y	N
Family Member Patent Publication Year	FY	Y	N
Family Member Type	FPT	Y	N
Family Publication Information	FIP	Y (3)	N
Field Availability	FA	Y	N
Inventor	IN	Y	Y
Inventor Address	INA	Y	Y
Inventor Current	INC	Y	Y
Inventor Old	INO	Y	Y

SELECT, ANALYZE, and SORT Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
IPC (ICA, ICI, ICM, ICMO, ICSO, IPCI)	IPC	Y	Y
IPC (ICM, ICS)	IC	Y	Y
IPC, Additional (supplementary)	ICA	Y	Y
IPC, Advanced Level Symbols	IPC.A	Y (6)	N
IPC, Advanced Level Symbols for Invention	IPC.AI	Y (6)	N
IPC, Core Level Symbols	IPC.C	Y (6)	N
IPC, Core Level Symbols for Invention	IPC.CI	Y (6)	N
IPC, Index (complementary)	ICI	Y	Y
IPC, Initial	IPCI	Y (6)	N
IPC, Main	ICM	Y	Y
IPC, Main, Old	ICMO	Y	Y
IPC, Secondary	ICS	Y	Y
IPC, Secondary, Old	ICSO	Y	Y
Language	LA	Y	Y
Main Claim	MCLM	Y	N
National Patent Classification	NCL	Y	Y
Note (legal status code)	NTE	Y	N
Opposition	OP	Y	Y
Other Source	OS	Y	Y
Passat Term	PST	Y	N
Patent Assignee	PA (CS)	Y	Y
Patent Assignee Address	PAA	Y	Y
Patent Assignee Current	PAC	Y	Y
Patent Assignee Number	PAN	Y	Y
Patent Assignee Old	PAO	Y	Y
Patent Assignee Type	PAT	Y	Y
Patent Countries	PCS	Y (7)	N
Patent Country	PC	Y	Y
Patent Information	PI	Y (3)	Y
Patent Information (Max)	PI.M	Y (3)	Y
Patent Information Publication Type	PIT	Y	Y
Patent Kind Code	PK	Y	Y
Patent Number	PN (PATS)	Y (3)	Y
Patent Publication Date	PD	Y	Y
Patent Sequence Reference	PSR	Y	N
Patent Type	PT	Y	Y
Pre-IPC8 Symbols for the ICM and first IPC8 values from 2006 onwards	IPC.F	Y (6)	N
Priority Country	PRC	Y	Y
Priority Date	PRD	Y	Y
Priority Kind Code	PRK	Y	Y
Priority Number	PRN (PRAI)	Y (3)	Y
Priority Type	PRT	Y	Y
Publication Year	PY	Y	Y
Reference Non-Patent Information	REN	Y	N
Reference Patents	REP	Y (3)	N
Referenced Patent Country	RPC	Y	N
Referenced Patent Date	RPD	Y	N
Referenced Patent Kind	RPK	Y	N
Referenced Patent Number	RPN	Y (3)	N
Referenced Patent Type	RPT	Y	N
Related Application Country	RLC	Y	N
Related Application Date	RLD	Y	N
Related Application Kind Code	RLK	Y	N
Related Application Number	RLN (RLI)	Y (3)	N
Related Application Type	RLT	Y	N

SELECT, ANALYZE, and SORT Fields (cont'd)

Field Name	Field Code	ANALYZE/ SELECT (1)	SORT
Source	SO	Y	Y
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Subclass of IPC	SCL	Y (8)	N
Subclass of Main IPC	SCLM	Y (8)	N
Subclass of Secondary IPC	SCLS	Y (8)	N
Subclass with Main Group of Add. IPC	SCGA	Y (8)	N
Subclass with Main Group of IPC	SCG	Y (8)	N
Subclass with Main Group of Main IPC	SCGM	Y (8)	N
Subclass with Main Group of Sec. IPC	SCGS	Y (8)	N
Supplementary Protection Certificate	SPC	Y	N
System Number	SN	Y	Y
Title	TI	Y (default)	Y
Title in English	TIEN	Y	Y
Titles	TLM	Y	Y
Update Date	UP	Y	N
Update Date Abstract	UPAB	Y	Y
Update Date Family Information	UPFI	Y	N
Update Date Note Information	UPNT	Y	N
Update Date Patent Assignee	UPPA	Y	N
Update Date Patent Information	UPPI	Y	N
Update date Patent Kind Code	UPPK	Y	N
Update Date SDI (last update)	UPS	Y	N

- (1) HIT may be used to restrict terms extracted to terms that match the search expression used to create the answer set, e.g., SEL HIT TI.
- (2) Appends /BI to the terms created by SELECT.
- (3) SELECTed and SORTed application, priority and patent numbers are in the format set by the Messenger SET PATENT command, either DERWENT or STN.
- (4) Selects or analyzes AP and PRN and appends /APPS to the terms created by SELECT.
- (5) Selects or analyzes Family Member Applications and Patent Numbers and appends /FN to the terms created by SELECT.
- (6) Appends /IPC to the terms created by SELECT.
- (7) Select or analyzes the country codes from PC and DS and appends /PCS to the terms created by SELECT.
- (8) Only valid for IPC Version 1-7.

Sample Records**DISPLAY BRIEF**

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AN  DE4316413  PATDPA    ED    19941124    EW    199447
SN  DE4316413.7      DED    19941124    DEW    199447
UPS  19981015          weitere UP-Felder:  HELP  UPD
TI  (A1) Einrichtung zur Entnahme von Probeexemplaren an
    Rotationsquerschneidern
IN  Mack, Richard Burkhard (*DE 6835 Bruehl)
    Klenk, Rainer (*DE 6837 St Leon-Rot)
PA  Heidelberger Druckmaschinen AG (*DE 69115 Heidelberg)
PAN  1004093  DE
PAT  (CORP) Juristische Person
EXF  27 Papier, Druck, Verpackung
SO  DE-Patentblatt 114 (1994) Heft 47, DE A1 Offenl.-Schrift, 1. Veroeff.
    Textseiten 11; Blattzahl 8; Zeichnungsseiten 4; Filmlochkarten 2
DT  Patent
LA  Deutsch
PIT  OS DE Offenlegungsschrift, 1. Veroeff.
PI  DE 4316413      A1 19941124  AO          (10) 1.Publ./ DE-Schrift
AI  DE 1993-4316413  A 19930517  ADP          (22) DE-Patentanmeldung

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PRAI DE 1993-4316413 A 19930517 IA (32) Nation. Erstanmeldung
 FI
 FIA DE 1993-4316413 A 19930517 ADP (22) DE4316413
 FIP DE 4316413 A1 19941124 AO (43) DE-Offenlegung
 RE
 REP DE 3010793 C2 SRP (56) Aus nation. Pruefungsverf.
 DE 724901 C SRP (56) Aus nation. Pruefungsverf.
 DE 2848010 B1 SRP (56) Aus nation. Pruefungsverf.
 DE 2229414 B2 SRP (56) Aus nation. Pruefungsverf.
 DE 1113358 B SRP (56) Aus nation. Pruefungsverf.
 DE 3527710 A1 SRP (56) Aus nation. Pruefungsverf.
 DE 2609136 4 McKrell, Thomas (*US Rye, N.H.)
 DE 2609136 A1 SRP (56) Aus nation. Pruefungsverf.
 DE 2330614 A1 SRP (56) Aus nation. Pruefungsverf.
 DE 1786264 A SRP (56) Aus nation. Pruefungsverf.
 DE 1561722 A SRP (56) Aus nation. Pruefungsverf.
 DD 2141111 A SRP (56) Aus nation. Pruefungsverf.
 US 4506882 A SRP (56) Aus nation. Pruefungsverf.
 US 2815949 A SRP (56) Aus nation. Pruefungsverf.

IC

ICM B65H029-66 (511) IPC-Hauptklasse
 ICS B65H029-68 (512) IPC-Nebenklasse
 B65H029-58 (512) IPC-Nebenklasse
 B65H035-08 (512) IPC-Nebenklasse
 B41F013-60 (512) IPC-Nebenklasse

AB (A1) 3Die Erfindung bezieht sich auf eine Einrichtung zur Entnahme von Probeexemplaren an Rotationsquerschneidern und Auslegern, die kontinuierlich zugefuehrte Materialbahnen in einer Schneidstation in einzelne Exemplare trennen. Anschliessend werden diese, annaeherd beruehrungslos und sich teilweise ueberlappend, in einer Exemplartransportebene gefoerdert. Die Exemplare sind einer der Schneidstation nachgeordneten Verzoegerungsstation zuleitbar. Die Erfindung wird dadurch charakterisiert, dass mindestens ein einer Exemplartransportebene (2) zugeordneter, die Exemplartransportebene (2) bei Aktivierung durchsetzender Schwenkknocken (21) die Foerderrichtung von Exemplaren (26) aendert.

FA AB; GI; ICS; INC; PST; REP

DISPLAY ALL

AN DE69930758 PATDPA ED 20060518 EW 200620
 SN DE69930758.9 DED 20070426 DEW 200717
 UPS 20071108 weitere UP-Felder: HELP UPD
 TI (T2)(CE) VERWENDUNG VON DAPTOMYCIN
 IN OLESON, B., Frederick (*US Concord, MA 01742)
 TALLY, P., Francis (*US Lincoln, MA 01733)
 PA Cubist Pharmaceuticals Inc. (*US Lexington, Mass.)
 PAN 12998842 US
 PAT (CORP) Juristische Person
 AG Vossius & Partner (81675 Muenchen)
 AGN 263125
 SO DE-Patentblatt 127 (2007) Heft 17, DE T2 DE-Uebersetzung der EP-PS
 DE-Patentblatt 126 (2006) Heft 20, DE CE DE-AKZ fuer EP-Patent
 DT Patent
 LA Deutsch
 NTE 19980925: FPRD (32) Erstes Prioritaetsdatum
 19990924: ADR (86) Anmeldetag d. EP-Anm. m. DE-Benennung
 20060405: PGR (87) EP-Patent mit DE-Wirk.
 20060518: PGRP (45) Publ. des DE-AKZ fuer erteiltes EP-Patent
 20070329: PGEI I363 Gegen d. Ert. wurde Einspruch erhoben

PATDPA

20070426: PGT2 (47) DE-Uebersetzung der EP-Patentschrift mit DE-Wirk.
 PIT PS T2 DE-Uebersetzung der EP-Patentschrift mit DE Wirkung
 PITX DET2-036 UEBERSETZUNG DER EUROPAEISCHEN PATENTSCHRIFT, - UEBER PCT KOMMEND

PI DE 69930758 T2 20070426 PGT2 (47) 036 (siehe PITX)
 AI DE 1999-69930758 E 19990924 ADRN (22) DE-AKZ fuer EP-Patent
 EP 1999-949913 AW 19990924 ADR (86) EURO-PCT-Anm. m. DE-Ben.
 WO 1999-US22366 A 19990924 ADWF (86) PCT-Anm. ohne DE-Best.
 PRAI WO 1999-US22366 W 19990924 CT (32) PCT-Anmeldung
 US 1999-125750P A 19990324 CP (32) Unionsprioritaet

FI

FIA WO 1999-US22366 A 19990924 ADW (86) WO2000018419
 DE 1999-69930758 E 19990924 ADRN (22) DE69930758
 FIP WO 2000018419 A1 20000406 AOW LEN (87) WO-Publik. mit DE-Best.:
 WO 2000018419 A2 20000406 AOW LXX (87) WO-Publik. mit DE-Best.:
 W: AE AL AM AT AU AZ BA BB BG BR BY CA CH CN CR CU CZ DE DK DM
 EE ES FI GB GD GE GH GM HR HU ID IL IN IS JP KE KG KP KR KZ
 LC LK LR LS LT LU LV MD MG MK MN MW MX NO NZ PL PT RO RU SD
 SE SG SI SK SL TJ TM TR TT TZ UA UG UZ VN YU ZA ZW
 RW: GH GM KE LS MW SD SL SZ TZ UG ZW
 RW: AM AZ BY KG KZ MD RU TJ TM
 RW: AT BE CH CY DE DK ES FI FR GB GR IE IT LU MC NL PT SE
 RW: BF BJ CF CG CI CM GA GN GW ML MR NE SN TD TG

DE 69930758 T2 20070426 PGT2 (47) 036 (siehe PITX)

IPC A61K0038-12 (511) IPC-Hauptklasse

IPC A61P0031-04 (512) IPC-Nebenklasse

MCLM (T2) Verwendung eines Daptomycins fuer die Herstellung eines
 Arzneimittels zum Behandeln einer bakteriellen Infektion in einem
 menschlichen Patienten mit Bedarf dafuer, wobei eine Dosis fuer die
 Behandlung 3 bis 75 mg/kg Daptomycin ist, wobei die Dosis wiederholt in
 einem Dosierungsintervall von einmal alle 24 Stunden bis einmal
 woechentlich verabreicht wird.

FA AG; AGN; INC; MCLM; PSR; SPC

SPC Arzneimittel Zertifikat Erteilung

DE122006000049.6 20071108 (DE69930758)

Cubist Pharmaceuticals, Inc., 65 Hayden Avenue , Lexington, Mass. 02421,
 US

BGA: EU/1/05/328/001 19.01.2006

EU/1/05/328/002 19.01.2006

Daptomycin

IPC: A61K0038-12

Laufzeit: bis 20210119

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